## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | OHNISHI ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,783,452	07-1998	Jons et al.	436/183
	В	US-6,054,379	04-2000	Yau et al.	438/623
	С	US-6,071,810	06-2000	Wada et al.	438/635
	D	US-6,159,871	12-2000	Loboda et al.	438/786
	E	US-6,485,815	11-2002	Jeong et al.	428/210
	F	US-6,506,680	01-2003	Kim et al.	438/692
	G	US-6,555,461	04-2003	Woo et al.	438/622
	Н	US-6,686,285	02-2004	Miyajima et al.	438/692
	ı	US-6,764,774	07-2004	Grill et al.	428/641
	J	US-6,858,539	02-2005	Minamihaba et al.	438/692
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.